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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)	Complete if Known	
	Application Number	Unknown
	Filing Date	Even Date Herewith
	First Named Inventor	Cole, Barrett
	Group Art Unit	Unknown
	Examiner Name	Unknown
Sheet 1 of 1		Attorney Docket No: H26482 DIV1 US (256.086US2)

US PATENT DOCUMENTS						
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
MDH	US-4,536,608	08/20/1985	Sheng, P., et al.	136	259	04/25/1983
↑	US-4,554,727	11/26/1985	Deckman, H., et al.	29	572	05/22/1984
↑	US-4,760,440	07/26/1988	Bigler, R. R., et al.	357	74	10/31/1983
↑	US-4,826,267	05/02/1989	Hall, R. L., et al.	350	1.6	11/30/1987
↑	US-5,151,917	09/29/1992	Perilloux, B., et al.	372	102	04/18/1991
↑	US-5,417,799	05/23/1995	Daley, T. W., et al.	216	24	09/20/1993
↑	US-5,895,233	04/20/1999	Higashi, R. E., et al.	438	107	09/29/1997
↓	US-6,359,735	03/19/2002	Gombert, A., et al.	359	580	01/14/1998
MDH	US-6,384,473	05/07/2002	Peterson, K. A., et al.	257	680	05/16/2000

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T ²
MDH	WO-95/17014	06/22/1995	Higashi, R. E., et al.	H01L	31/020 3	

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
MDH		KWA, T. A., et al., "Integrated Grating/Detector Array Fabricated in Silicon Using Micromachining Techniques", <i>Sensors and Actuators A</i> , 31, (1992), 256-266		
MDH		MOTAMED, M. E., et al., "Antireflection surfaces in silicon using binary optics technology", <i>Applied Optics</i> , 31(22), (August 1992), pp. 4371-4376		

EXAMINER

Monica D. Damico

DATE CONSIDERED

8/18/04

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached